

PHP50N06-VB Datasheet N-Channel 60-V (D-S) MOSFET

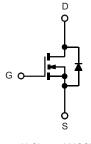
PRODUCT	SUMMARY	
V _{DS} (V)	R_{DS(on)} (Ω)	I _D (A) ^a
60	0.011 at V _{GS} = 10 V	60
00	0.013 at V _{GS} = 4.5 V	50

FEATURES

- 175 °C Junction Temperature
- Trench Power MOSFET
- Material categorization:







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25	°C, unless other	vise noted)		
Parameter		Symbol	Limit	Unit
Gate-Source Voltage		V _{GS}	± 20	V
Continuous Durin Company (T. $= 175^{\circ}$ Colb	T _C = 25 °C	I _D	60	
Continuous Drain Current (T _J = 175 °C) ^b	T _C = 100 °C		50ª	
Pulsed Drain Current Continuous Source Current (Diode Conduction) Avalanche Current		I _{DM}	200	A
		۱ _S	50ª	
		I _{AS}	50	
Single Avalanche Energy (Duty Cycle ≤ 1 %)	L = 0.1 mH	E _{AS}	125	mJ
Maximum Power Dissipation	T _C = 25 °C	Pn -	136	w
	T _A = 25 °C		3 ^b , 8.3 ^{b, c}	vv
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum lumation to Amelianta	$t \le 10 \text{ sec}$	R _{thJA}	15	18	
Maximum Junction-to-Ambient ^a	Steady State	• • • thJA	40	50	°C/W
Maximum Junction-to-Case		R _{thJC}	0.85	1.1	

Notes:

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. $t \leq 10$ s.

Static Image: Static<	SPECIFICATIONS (T _J = 25 °C,	unless oth	erwise noted)					
$\begin{array}{ c c c c } \hline Drain-Source Breakdown Voltage V_{DS} & $V_{GS} = 0 \ V, \ b_{D} = 250 \ \mu A$ & 60$ & $$$$$$$$$$$$$$$$$$$$$$$$$$$$$$$	Parameter	Symbol	Test Conditions	Min.	Typ.ª	Max.	Unit	
$ \begin{array}{c c c c c c } \hline Gate Threshold Voltage & V_{GS(th)} & V_{DS} = V_{GS}, I_{D} = 250 \ \mu A & 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 &$	Static			•				
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$				V	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1		3	Unit V nA μA A Ω S pF nC nS	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 20 V			± 100	nA	
$ \begin{array}{ c c c c c } \hline V_{DS} = 60 \ V, \ V_{GS} = 0 \ V, \ U_{J} = 175 \ ^{\circ} C & & & & & & & & & & & & & & & & & & $			V _{DS} = 60 V, V _{GS} = 0 V			1		
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V, T _J = 125 °C			50	μΑ	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $			V _{DS} = 60 V, V _{GS} = 0 V, T _J = 175 °C			250		
$ \begin{array}{ c c c c } \hline Prime \mbox{Converse} $	On-State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	60			А	
$ \begin{array}{ c c c c c } \hline Prain-Source On-State Resistance^b & R \\ \hline PS(on) & V \\ \hline V \\ GS = 10 V, \\ I_D = 20 A, \\ T_J = 175 \ ^{\circ}C & 0.018 \\ \hline V \\ GS = 4.5 V, \\ I_D = 15 A & 0.013 \\ \hline V \\ GS = 4.5 V, \\ I_D = 15 A & 0.013 \\ \hline V \\ GS = 4.5 V, \\ I_D = 15 A & 0.013 \\ \hline V \\ GS = 15 V, \\ I_D = 20 A & V \\$			V _{GS} = 10 V, I _D = 20 A		0.011			
$ \begin{array}{ c c c c c c } \hline \begin{tabular}{ c c c c c c } \hline \begin{tabular}{ c c c c c c c c } \hline \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$		D	V _{GS} = 10 V, I _D = 20 A, T _J = 125 °C		0.014			
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Drain-Source On-State Resistance	DS(on)	V _{GS} = 10 V, I _D = 20 A, T _J = 175 °C		0.018		Ω	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$			V _{GS} = 4.5 V, I _D = 15 A		0.013			
$ \begin{array}{ c c c c c c } \hline Input Capacitance & C_{iss} & V_{GS} = 0 \ V, \ V_{DS} = 25 \ V, \ f = 1 \ MHz & 570 & 325 &$	Forward Transconductance ^b	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		60		S	
$ \begin{array}{ c c c c c c } \hline Output Capacitance & C_{oss} & V_{GS} = 0 \ V, \ V_{DS} = 25 \ V, \ f = 1 \ MHz & 570 & 325 $	Dynamic	1		•	•			
$ \begin{array}{c c c c c c c } \hline Reverse Transfer Capacitance & C_{rss} & & & & & & & & & & & & & & & & & & $	Input Capacitance	C _{iss}			4200			
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz		570		pF	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}			325			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge ^c	Qg			47			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Charge ^c	Q _{gs}	V _{DS} = 30 V, V _{GS} = 10 V, I _D = 50 A		10		nC	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Drain Charge ^c	Q _{gd}			12			
$\begin{tabular}{ c c c c c c c c c c c c c c c c c c c$	Turn-On Delay Time ^c	t _{d(on)}			10	20	- ns	
Fall Time° t_f 20Source-Drain Diode Ratings and Characteristics ($T_C = 25$ °C) I_{SM} $I_F = 20 \text{ A}, V_{GS} = 0 \text{ V}$ Diode Forward Voltage V_{SD} $I_F = 20 \text{ A}, V_{GS} = 0 \text{ V}$ 1	Rise Time ^c	tr	V_{DD} = 30 V, R _L = 0.6 Ω		15	25		
Source-Drain Diode Ratings and Characteristics ($T_C = 25 \ ^{\circ}C$)Pulsed CurrentI SDDiode Forward VoltageV SDIF = 20 A, VGS = 0 V1	Turn-Off Delay Time ^c	t _{d(off)}	$I_D \cong 50 \text{ A}, V_{\text{GEN}} = 10 \text{ V}, \text{R}_{\text{g}} = 2.5 \Omega$		35	50		
Pulsed Current I _{SM} I Diode Forward Voltage V _{SD} I _F = 20 A, V _{GS} = 0 V 1	Fall Time ^c	t _f	1		20	30		
Diode Forward Voltage V_{SD} $I_F = 20 \text{ A}, V_{GS} = 0 \text{ V}$ 1	Source-Drain Diode Ratings and Cha	aracteristics ((T _C = 25 °C)					
	Pulsed Current					60	А	
Reverse Recovery Time t_{rr} $I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$ 45	Diode Forward Voltage	V _{SD}			1	1.5	V	
	Reverse Recovery Time	t _{rr}	I _F = 20 A, di/dt = 100 A/μs		45	100	ns	

Notes:

a. For design aid only; not subject to production testing.

b. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

c. Independent of operating temperature.

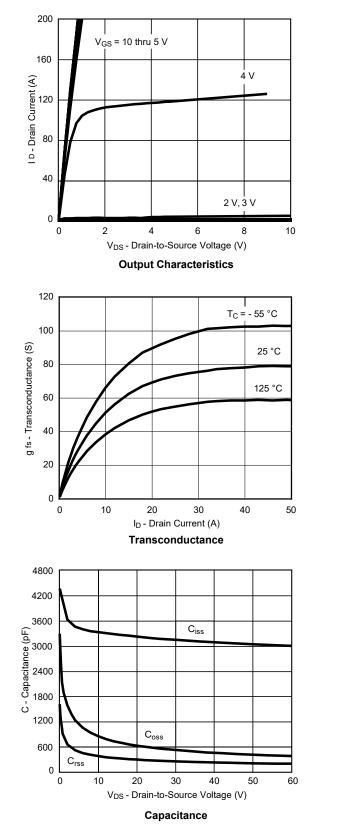
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

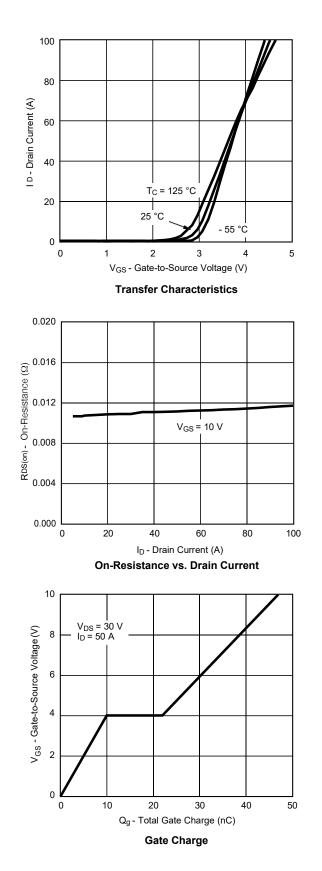
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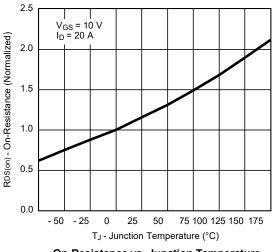
TYPICAL CHARACTERISTICS (25 °C unless noted)



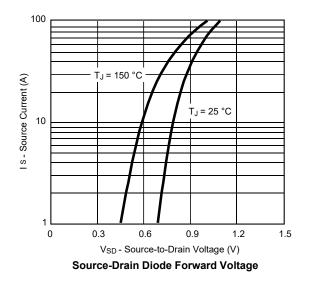




TYPICAL CHARACTERISTICS (25 °C unless noted)

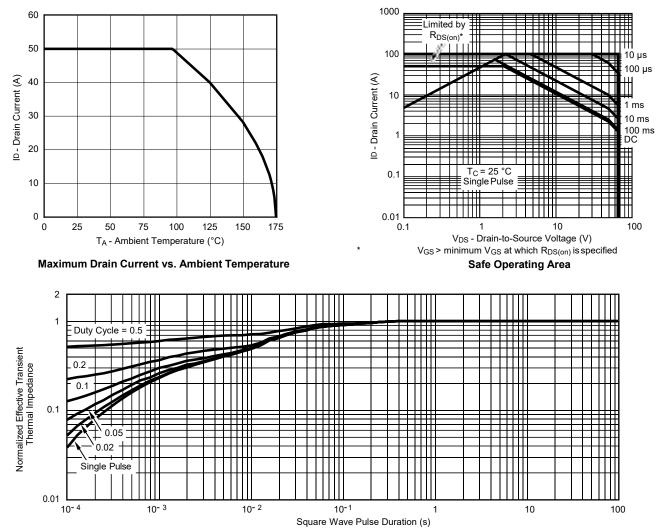


On-Resistance vs. Junction Temperature



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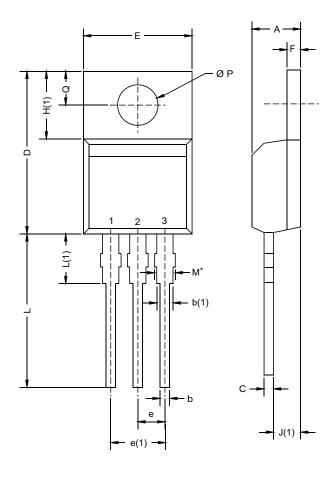
THERMAL RATINGS



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



DIM.	MILLIM	ETERS	INC	INCHES		
	MIN.	MAX.	MIN.	MAX.		
А	4.24	4.65	0.167	0.183		
b	0.69	1.02	0.027	0.040		
b(1)	1.14	1.78	0.045	0.070		
С	0.36	0.61	0.014	0.024		
D	14.33	15.85	0.564	0.624		
E	9.96	10.52	0.392	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.10	6.71	0.240	0.264		
J(1)	2.41	2.92	0.095	0.115		
L	13.36	14.40	0.526	0.567		
L(1)	3.33	4.04	0.131	0.159		
ØР	3.53	3.94	0.139	0.155		
Q	2.54	3.00	0.100	0.118		
ECN: X15- DWG: 603	0364-Rev. C, 1	14-Dec-15				

Note

• M* = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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